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01/26/04*

CLAIMS AMENDMENTS

Please amend the claims as follows:

1. (Currently Amended) A method of conducting a circuit continuity test on an analog device having a first and a second node, said first and second node being coupled to a test circuit having a plurality of inputs, comprising the steps of:

providing a first voltage via a first resistor to said first node using a first input of said test circuit, wherein said first node couples to a diode in the analog device, said diode connecting said first node directly to ground; and

measuring a second voltage at the first node via a second input of said test circuit, wherein said measured second voltage and corresponding operational state of said diode is indicative of the internal circuit continuity of said analog device.

2. (Original) The method of claim 1 wherein said measured second voltage is a diode drop below ground when the analog device first node has continuity.

3. (Original) The method of claim 2 wherein the measured second voltage is the applied said first voltage when said analog device first node does not have continuity.

4. (Original) The method of claim 1 wherein said second voltage is measured at said first node without using a relay.

5. (Original) The method of claim 1 wherein said second voltage is measured via a second resistor being in parallel with said first resistor.

6. (Original) The method of claim 1 wherein said first voltage is negative voltage.

7. (Original) The method of claim 2 further comprising the step of simultaneously applying a third voltage to said second input node via a third resistor, and measuring a fourth voltage at said second node.